

**Notice of References Cited**

Application/Control No.

09/533,148

Applicant(s)/Patent Under  
Reexamination  
LIN, EDDIE HUEY CHIUN

Examiner

Yasin M Barqadle

Art Unit

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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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